S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/765,347	OWEN ET AL.
Examiner	Art Unit
Ninh H. Nauven	3745

	SEAR	CHED	
Class	Subclass	Date	Examiner
416	236R, 223R, 233	5/26/2005	NHN
•			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
	1		

SEA (INCLUDING :	RCH NOT SEARCH :	ES STRATEGY)
		DATE	EXMR
East search		5/26/2005	NHN
		·	